



Retraction

Retraction: Leong, W.S.; Arrabito, G.; Prestopino, G. Artificial Intelligence Algorithm Enabled Industrial-Scale Graphene Characterization. *Crystals* 2020, 10, 308

Crystals Editorial Office

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The *Crystals* Editorial Office has been made aware that the data and results in this published paper [1] by Dr. Wei Sun Leong, Dr. Giuseppe Arrabito, and Dr. Giuseppe Prestopino were used by Dr. Wei Sun Leong without authorization from Massachusetts Institute of Technology (MIT). The subject publication contains unpublished images and data from an MIT project lead by other MIT authors on which Dr. Wei Sun Leong was participating during her 2017–2019 appointment at MIT. The project was supported in part by funds to MIT from two federal agencies of the United States. Dr. Giuseppe Arrabito and Dr. Giuseppe Prestopino (the Guest Editors of the Special Issue "2D Materials: From Structures to Functions") were totally unaware of this situation at the time of paper submission and were misled. They were made aware of the issue after paper publication and are thankful to the *Crystals* Editorial Office for having shed light on this.

Therefore, the *Crystals* Editorial Office has taken the decision to retract [1] in order to preserve academic integrity. We apologize for any inconvenience caused by the removal of this article. The retraction of the article was approved by the Editor-in-Chief of *Crystals* and has been taken in agreement with all authors except Dr. Wei Sun Leong.

MDPI is a member of the Committee on Publication Ethics and takes the responsibility to enforce strict ethical policies and standards very seriously. To ensure the addition of only high quality scientific works to the field of scholarly publication, the published paper [1] is retracted and shall be marked accordingly.

References

 Leong, W.S.; Arrabito, G.; Prestopino, G. Artificial Intelligence Algorithm Enabled Industrial-Scale Graphene Characterization. Crystals 2020, 10, 308. [CrossRef]



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